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JAPANESE PATENT OFFICE

## PATENT ABSTRACTS OF JAPAN

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(71)Applicant:

FURUKAWA ELECTRIC CO LTD:THE

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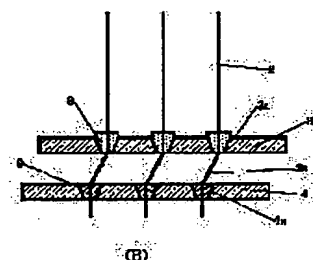
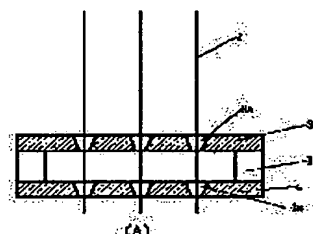
ZAMA SATORU  
SUZUKI TAKUYA  
YUZAWA HITOSHI

## (54) MANUFACTURE OF PROBER

(57)Abstract:

**PROBLEM TO BE SOLVED:** To provide a method for manufacturing a prober capable of accurately and stably inspecting and simply manufacturing by reducing the friction of a probe needle with the through hole of a guide plate without bringing adjacent needles into contact with one another.

**SOLUTION:** The method for manufacturing a prober comprises the steps of inserting probe needles 2 extended linearly into the through holes 3a, 4a of two guide plates 3, 4 disposed in parallel via a predetermined interval, then fixing the needles 2 to the inner walls of the holes 3a, 4a of the plates 3, 4, thereafter relatively moving the plates 3, 4 to form bent parts 2a at the needles 2, then releasing the fixing of at least the one plate to the hole, and then engaging a frame 5 between the guides 3 and 4 to support it in parallel.



## LEGAL STATUS

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